

2011 —YASUDA Hidehiro

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1. M. Imamura, J. Nakamura, S. Fujimasa, H. Yasuda, H. Kobayashi, and Y. Negishi, Photoluminescence dynamics of organic molecule-passivated Si nanoclusters, European Physical Journal D, 63, 289-292, 2011
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3. Noriko Nitta, Yohta Aizawa, Tokiya Hasegawa and Hidehiro Yasuda, Structural changes induced by low energy electron irradiation in GaSb, Philosophical Magazine Letters, 91, 676–681, 2011
4. H. Yasuda, K. Matsumoto, T. Furukawa, M. Imamura, N. Nitta and H. Mori, Thickness-dependent structural transition in GaAs nanocrystals grown on Si(111) surface, Journal of Crystal Growth, 314, 365-369, 2011
5. H. Yasuda and H. Mori, Electronic-excitation-induced processing in GaSb compound nanoparticles, Journal of Nanomaterials, Article ID 901930, 1-4, 2011
6. N. Nitta, E. Taguchi, H. Yasuda, H. Mori, Y. Hayashi, T. Yoshiie and M. Taniwaki, Secondary defects induced by ion and electron irradiation of GaSb, Philosophical Magazine Letters, 91, 223-228, 2011
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1. H. Yasuda, "In situ TEM observations of electronic-excitation-induced structural transition process in GaSb nanoparticles", Proc. of 10th Asia-Pacific Microscopy Conference, 96-1-2, 2012
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